COPT

CENTER FOR ORGANIC ELECTRONICS | UNIVERSITY OF COLOGNE

DATA SHEET

Stylus Profilometer

Bruker Corporation

Dektak XT

copt-zentrum.de

Universität zu Köln

3D
Mapping

Technical Data — Stylus profilometer

Company — Bruker Corporation

Model — Dektak XT

Application:	Tactile determination of the surface topography (layer thickness, waviness and roughness...) and 3D mapping on all solid surfaces
Stylus force:	1 to 15 mg with LIS sensor
Measuring length:	55 mm, through connection up to 200 mm
Max. sample size (W x L x H):	200 x 200 x 50 mm^3
Stylus sensor:	Low Inertia Sensor (LIS3)
Stylus options:	Stylus radius options from 50 nm bis 25 µm; High Aspect Ratio (HAR) tips 200 µm x 20 µm
Sample X/Y stage:	100 mm X 100 mm X/Y, manual leveling (manual / motorized)
Sample r-theta stage:	Continous 360 degrees (manual / motorized)
Data points per scan:	120.000 maximum
Step height repeatability:	4 Å, 1 sigma on steps ≤ 1 µm (30 scans using a 12,5 µm stylus)
Vertical range:	1 mm
Vertical resolution:	1 Å (@ 6.55 µm range)
Besondere merkmale:	The unit is enclosed and mounted on a vibration damper
Sample viewing:	Digital magnification, 0.275 to 2.2 mm
Accessories:	Styli of different radii and designs, reference sample

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